## Application/Control No. Applicant(s)/Patent Under Reexamination 10/594,595 KATO ET AL. Notice of References Cited Art Unit Examiner Page 3 of 3 Shin-Lin Chen 1632 **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY US-Α US-В US-С US-D US-Е US-US-G US-Н US-US-J US-Κ US-L US-М FOREIGN PATENT DOCUMENTS Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U Skolnick et al., 2000, Trends in Biotech, Vol. 18, p. 34-39. Fiedler et al., 2002, Journal of Cellular Biochemistry, Vol. 87, p. 305-312. hange (a) applied Gerber et al., 2002, US 20020132978 A1. 09-2002

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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